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ABBREVIATIONS AND SYMBOLS

BET	Brunauer-Emmett-Teller
C	amount of carbon
C	a constant, related to the free energy of adsorption
c	speed of light
$^{\circ}\text{C}$	Degrees Celsius
d_{hkl}	interplanar distance between (hkl) planes
d	the lattice planar spacing
CB	conduction band
e^{-}	Electron
e_{cb}^{-}	Conduction band electron
eV	Electron Volt
E	binding energy
EDS	Energy Dispersive X-ray Spectroscopy
EG	Ethylene Glycol
E_b	Binding energy
E_g	Optical band gap of the semiconductor
h	Plank's constant (6.63×10^{-34} Js)
$h\nu$	photon energy
h^{+}	hole
h_{vb}^{+}	valence band hole
JCPDS	Joint Committee Powder Diffraction Standards
K	kelvin
K	absorption coefficient
k	conductivity value
keV	kilo electron volt
kV	kilo-volt
mg	milligram

min	minute
ml	milliliter
mS	millisiemen
nm	nanometer (10^{-9} m)
N_a	Avogadro's number (6.02×10^{23})
$\cdot O_2^-$	superoxide radical
$\cdot OH$	hydroxyl radical
SEM	Scanning Electron Microscopy
SSA	Specific Surface Area
S_{BET}	BET surface area
TEM	Transmission Electron Microscopy
UV	Ultraviolet
VB	valence band
XRD	X-ray diffraction
Z	atomic number
λ	wavelength
μg	microgram (10^{-6} g)
$\mu g C$	microgram of carbon
μm	micron (10^{-6} meter)
$\mu S/cm$	microSiemens /centimeter
θ	the Bragg angle for the reflection
ν	frequency